

## VACUUM XRF PLATING THICKNESS INSTRUMENT/RoHS ANALYZER CODE XRF-VF300

VACUUM SYSTEM MANUAL ZOOM

- According to DIN ISO 3497, DIN 50987, and ASTM B568
- Used for RoHS analysis, electroplating/electrophoretic plating analysis
- Minimum measurement area of 0.2mm² with micro-focus X-ray generator and advanced optical switching focusing system
- Equipped with manual zoom technology, it allows for non-destructive testing of irregular components with depths from 0 to 30mm
- Core EFP algorithm for simultaneous analysis of 23 plating layers, 24 elements
- Equipped with an intelligent vacuum system, it enhances the precision of analysis for platings of light elements, resulting in more stable data



## **SPECIFICATION**

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RoHS analysis	range of elemental analysis	Cd, Pb, Hg, Br, Cr, Cl, As, Sb
	detection limit	2ppm
	content range	2ppm~99%
Plating analysis	range of elemental analysis	Li (3)-U (92)
	detection limit	0.005μm
	range of plating thickness	0.01~80μm
Algorithm		EFP
Analysis time		5~300s
Detector		SDD (silicon drift detector)
X-ray device		microfocus enhanced ray tube
Collimator		automatic switching of 4 types of collimators: Ø0.5mm, Ø1.5mm, Ø3mm, Ø8mm
Spot spread at the nearest measurement distance		<10%
Sample observation		1/2.7" color CCD with zoom functionality
Distance to zoom		0~30mm
Focusing method		highly sensitive lenses with manual focusing
Vacuum system		intelligent vacuum system
Height of vacuum cavity		80mm
Working environment		15~30°C, <70%RH
Power supply		AC220V, 50Hz, 95W
Dimension (W×D×H)		550×410×370mm
Weight		50kg

## STANDARD DELIVERY

Main unit	1 pc
Computer	1 set
Software	1 set
Printer	1 pc
Vacuum pump	1 pc
Accessory case	1 pc
12 elemental tablet	1 set
Ni standard sheet	1 pc
Ag standard sheet	1 pc
ERM-EC681m standard sheet	1 pc

## **OPTIONAL ACCESSORY**

Plating solution measuring cup	XRF-PT230-MC
Solution test membrane	XRF-PT230-SF
Au standard sheet	MSS-P01
Cr standard sheet	MSS-P02
Cu standard sheet	MSS-P03
Zn standard sheet	MSS-P04